



WP 15.2 Progress

CERN (Alban Sublet)

INFN (Cristian Pira)



ARIES WP15 Meeting



5 Different cleaning batches

2

process no.	A	B	C	D	E	F	G	H	I	J	K	L	M	N	O	P	Q	R	S	T	U	V	W	X	Y	Z	AA																			
			Initially 60 samples with a size of 53 mm x 53 mm cut from the same sheet																																											
1	Sample number	C1	C2	C3	C4 (spar)	C5 (spar)	C6 (spar)	C7	C8	C9	C10 (spar)	C11 (spar)	C12 (spar)	C13 (spar)	C14 (spar)	C15	C16	C17	C18	C19 (spar)	C20 (spar)	C21 (spar)	C22 (spar)	C23 (spar)	C24 (spar)	C25 (spar)																				
2	SUBU Cleaning Procedure	CERN SuBu5																																												
3	Tumbling Cleaning Procedure																																													
4	EP Cleaning Procedure																																													
5	EP+SUBU Cleaning Procedure																																													
6	Surface characterisation																																													
7	shipping samples																																													
8	Surface characterisation	oxygen free copper (600 mm x 600 mm x 1 mm) from CERN shop																																												
9	Laser polishing																																													
10	Surface characterisation																																													
11	shipping samples	L1	L2	L3 (spar)	L4	L5 (spar)	L6 (spar)	L7	L8 (spar)	L9 (spar)	L10	L11	L12 (spar)	L13 (spar)	L14 (spar)	L15 (spar)	L16	L17	L18 (spar)	9 spare samples																										
12	20 nm Nb coating	SuBu5																																												
13	shipping samples	Tumbling																																												
14	Surface characterisation	EP																																												
15	Nb interlayer laser tratment	EP+SUBU																																												
16	Surface characterisation																																													
17	shipping samples	Siegen	Siegen																							Siegen	Siegen	Siegen																		
18	Surface characterisation	Siegen	Siegen																							Siegen	Siegen	Siegen																		
19	Heat treatment	Siegen	Siegen																							Siegen	Siegen	Siegen																		
20	3 μm Nb coating	Siegen	Siegen																							Siegen	Siegen	Siegen																		
21	Surface characterisation	Siegen	Siegen																							Siegen	Siegen	Siegen																		
22	Cutting samples	Siegen	Siegen																							Siegen	Siegen	Siegen																		
23	shipping samples																																													
24	SC characterisation **	IEE, STFC																																												
25	shipping samples																																													
26	Post deposition laser treatment ***	RTU	RTU																							RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	
27	Surface characterisation	RTU	RTU																							RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU
28	shipping samples																																													
29	SC characterisation **	IEE, STFC																																												
		Siegen	Siegen	Siegen	STFC	STFC	STFC	INFN	INFN	INFN	Siegen	Siegen	Siegen	STFC	STFC	STFC	INFN	INFN	INFN																											
		Siegen			STFC			INFN	INFN		Siegen			STFC	STFC		INFN	INFN																												
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		Siegen	Siegen		STFC	STFC		INFN	INFN		Siegen	Siegen		STFC	STFC		INFN	INFN																												
		IEE, STFC	IEE, STFC		IEE, STFC	IEE, STFC		IEE, STFC			IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC		IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC																			
		RTU	RTU		RTU	RTU		RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU																			
		RTU	RTU		RTU	RTU		RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU	RTU																			
		IEE, STFC	IEE, STFC		IEE, STFC	IEE, STFC		IEE, STFC			IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC		IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC	IEE, STFC																			





Samples polished

- **25 samples polished at CERN with SUBU process**
- **5 samples polished at INFN with SUBU process**
- **8 samples polished at INFN with ElectroPolishing (EP) process**
- **4 samples polished at INFN with SUBU + EP process**
- ***6 samples (including 2 spare samples)***
will be treat at INFN with tumbling process in March



CERN samples dispatched

Sample dispatched in August as following (all polished with SUBU):

- **8 samples (including 2 spare samples) sent to RTU**
- **6 samples (including 2 spare samples) sent to Siegen**
- **6 samples (including 2 spare samples) sent to STFC**
- **5 samples left at CERN**



INFN samples dispatched

Sample dispatched in October as following:

- **6 samples (including 2 spare samples) sent to Siegen**
(3 samples of SUBU batch and 3 of EP batch)
- **3 samples (including 1 spare sample) sent to STFC**
(3 samples of EP batch)
- **2 samples left at LNL**
(2 samples of EP+SUBU batch)
- **6 spare samples left at LNL**
(2 spare samples of each batch)